Charts for Analysing Crystallite Distribution Function Plots for Cubic Materials

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(Received 16 July 1970 and accepted for publication 17 August 1970)

Charts are given which provide a rapid and unambiguous way of attributing ideal orientations to regions of crystallite orientation distribution plots for materials having cubic symmetry.

The use of the crystallite orientation distribution function in textural studies is becoming well established (Roe, 1966; Bunge & Haessner, 1968; Morris & Heckler, 1968; Bunge & Roberts, 1969; Kallend & Davies, 1969). The crystallite distribution function expresses the probability of a crystallite having the orientation described by the Euler angles \( \psi \), \( \theta \) and \( \varphi \). These angles relate the crystallographic axes of the crystallite to chosen axes in the sample sheet material, e.g. normal direction, rolling direction, transverse direction (Fig. 1). Fig. 1 gives the normal mathematical convention for Euler angles (Mathews & Walker, 1965) as adopted by Roe (1966) and subsequently by Morris & Heckler (1968) and Kallend & Davies (1969). Bunge & Haessner (1968) and Bunge & Roberts (1969) on the other hand have taken the \( \theta \)-rotation about the crystallographic \( a \) axis. The two conventions are related by

\[
\begin{align*}
\psi_{\text{Roe}} &= \psi_{1, \text{Bunge}} - \pi/2 \\
\theta_{\text{Roe}} &= \Phi_{\text{Bunge}} \\
\varphi_{\text{Roe}} &= \varphi_{2, \text{Bunge}} + \pi/2
\end{align*}
\]

and the necessary conversions must be made in comparing the results from the different sources.

The results of analyses of crystallite orientation distributions are normally represented graphically by plotting the probabilities in Eulerian space and taking constant sections of one of the Euler angles, most usually constant-\( \psi \) sections.

Using these sections the textural elements can be considered in terms of ideal orientations \( (hkl) [uvw] \), which correspond to Euler angles given by

\[
\begin{align*}
\cos \psi &= \frac{w}{(u^2 + v^2 + w^2)^{1/2}} \cdot \frac{(h^2 + k^2 + l^2)^{1/2}}{(h^2 + k^2)^{1/2}} \\
\cos \theta &= \frac{l}{(h^2 + k^2 + l^2)^{1/2}} \\
\cos \varphi &= \frac{-h}{(h^2 + k^2)^{1/2}} \\
\text{For the special case in which } h=k=0 \text{ then} \\
\cos (\psi + \varphi) &= \frac{u}{(u^2 + v^2 + w^2)^{1/2}}
\end{align*}
\]

These ideal orientations are those commonly used in rolling studies in which \( (hkl) \) refers to a crystallographic plane lying in the plane of the sheet specimen and \( [uvw] \) is a crystallographic direction in this plane and parallel to the rolling direction.

Alternatively, an ideal orientation can be found from known Euler angles using

\[
\begin{align*}
h &= -\sin \theta \cos \varphi \\
k &= \sin \theta \sin \varphi \\
l &= \cos \theta \\
u &= \cos \psi \cos \theta \cos \varphi - \sin \psi \sin \varphi \\
v &= -\cos \psi \cos \theta \sin \varphi - \sin \psi \cos \varphi \\
w &= \cos \psi \sin \theta
\end{align*}
\]

and rationalizing the resulting indices.

In most cases this analysis is unnecessarily time-consuming and to facilitate the analysis of crystallite distribution plots a set of charts has been prepared for cubic materials. These charts show all the textural components \( (hkl) [uvw] \) for cubic materials formed by permuting \( h, k, l, u, v, w \) through 3 to \(-3\). The resulting Euler angles are taken within the ranges

\[
0 \leq \psi \leq \pi/2 \quad 0 \leq \theta \leq \pi/2 \quad 0 \leq \varphi \leq \pi/2
\]

which are adequate for a complete description of textures with cubic symmetry.

Fig. 1. Diagram illustrating the three successive rotations through the Euler angles \( \psi \), \( \theta \) and \( \varphi \) which relate the crystal axes to the sheet reference axes. Axes \( a, b, c \), coincident with the sheet reference axes are rotated successively by \( \psi \) about \( c \) to \( a', b', c' \); by \( \theta \) about \( b' \) to \( a'', b'', c'' \); by \( \varphi \) about \( c'' \) to \( a, b, c \); \( \tilde{a}, \tilde{b}, \tilde{c} \) represent the final position of the crystal axes.
Fig. 2. Constant-\( \phi \) sections through the Eulerian space (a) \( \phi = 0^\circ \), (b) \( \phi = 20^\circ \), (c) \( \phi = 25^\circ \), (d) \( \phi = 35^\circ \), (e) \( \phi = 45^\circ \), (f) \( \phi = 55^\circ \).
Each ideal orientation, \((hkl) [uvw]\), is represented by a unique point in the region of Eulerian space considered.

Fig. 2(a) to (i) gives constant-\(\varphi\) sections through the Eulerian space. As can be seen from the expressions given above, specifying \((hkl)\) determines \(\theta\) and \(\varphi\), while \([uvw]\) is needed to determine \(\psi\). Hence the \((hkl)\) are represented by lines of constant \(\theta\) in the constant-\(\varphi\) sections and the corresponding \([uvw]\) as points along these lines. Each point in the charts thus represents a component \((hkl) [uvw]\). It is not practical to produce constant-\(\varphi\) sections for every \(\varphi\) value and hence where the
actual $\varphi$ value differs by a small amount from the value on this section, this is given on the chart. In practice this means that the point representing the appropriate $(hkl)\, [uvw]$ lies either just above or just below the given section.

As referred to earlier, some ambiguity exists for the ideal orientations $(001)\, [uc0]$ and these appear as points on all sections. Fig. 3 shows the $\theta=0$ section which gives the lines representing these orientations.

Fig. 4 shows the positions of $(hkl)$ lines for all $\psi$ values. These are the lines which appear as constant-$\theta$ on the constant-$\varphi$ sections.

Using these sets of charts, ideal orientations can be attributed to the high density regions of crystallite orientation distribution function plots both rapidly and unambiguously. This will enhance the understanding of the data contained in the plots as well as permitting comparison with textural data obtained by more conventional methods (Dillamore & Roberts, 1965).

The authors wish to thank the Director of the University of Cambridge Computing Service for the use of the TITAN computer. Thanks are also due to the Science Research Council (JSK) and the British Steel Corporation South Wales Group (DJG) for providing financial support during the course of this work.

References


Small-Angle Scattering of Two-Phase Systems: Determination and Significance of Systematic Deviations from Porod's Law

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(Received 12 January 1970 and accepted for publication 8 September 1970)

Density transition of finite width between the phases and density fluctuations within the phases produce systematic deviations from Porod's law, which can be detected by suitable intensity plots. These plots permit the correction of the intensity and the determination of structural parameters related to the causes of the deviations.

Introduction

The theory of small-angle scattering by isotropic two-phase systems (Porod, 1951, 1952a, b) predicts a decrease of the intensity proportional $\theta^{-4}$ at large values of $\theta$, known as Porod's law. Assuming a single scattering process and the applicability of the kinematic scattering theory, the scattering intensity $I$ is given by

$$I = \mathcal{F}(\Delta \rho^{*2})$$

where $\Delta \rho$ is the difference between the local electron density and the average, $\mathcal{F}$ is a three-dimensional Fourier transform

$$\int \left(\Delta \rho^{*2}\right) \exp\{2\pi i r s\} dV_r$$

and $*^2$ stands for self-convolution or autocorrelation.

With this normalization of $I$, Porod's law takes the form

$$I(s \to \infty) = \frac{S}{8\pi^3 s^4 (\varrho_1 - \varrho_2)^2}$$

where $s = 2\theta/\lambda$ and $S$ is the total area of the interface between the phase with density $\varrho_1$ and the phase with density $\varrho_2$.

Very often the intensity is not determined in absolute units and Porod's law is used in the form

$$\lim_{s \to \infty} \frac{2\pi s^4 I(s)}{4\pi} = \frac{S}{4\pi V (1 - c) V} = \frac{1}{l_p}$$

where $S/V$ is the area of the interface per unit volume, $c$ the volume fraction of one of the phases and $l_p$ the 'range of inhomogeneity', a parameter related to...